

## ABSTRACT OF THE DISCLOSURE

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The present invention makes it possible to obtain an aging deterioration margin amount including an allowance for aging deterioration in a simplified manner. Moreover, in order to allow an appropriate inspection taking aging deterioration into account, a delay deterioration rate predicting part 101 outputs signal path delay information before deterioration 302 and signal path delay deterioration rate information 303 for each signal path, based on LSI design information 301. A delay vs. delay deterioration rate analyzing part 102 outputs delay vs. delay deterioration rate relationship information 304 showing the correlation between the delay and the delay deterioration rate based on the information. A delay deterioration rate extracting part 103 extracts a delay deterioration rate of a predetermined signal path and outputs it as delay deterioration margin 305. A delay deterioration margin amount calculating part 104 calculates a delay deterioration margin amount by using the delay deterioration margin 305 as a derating factor G. Furthermore, a inspection operation frequency calculating part 105 calculates an operation frequency for inspection using the delay deterioration margin 305 as a derating factor G.